

Evaluating the Impact of Transition Delay Faults in GPUs

*Original*

Evaluating the Impact of Transition Delay Faults in GPUs / Rodriguez Condia, Josie E.; Reorda, Matteo Sonza. - (2023), pp. 353-358. (Intervento presentato al convegno International Conference on VLSI Design and 2023 22nd International Conference on Embedded Systems (VLSID) tenutosi a Hyderabad (India) nel 08-12 January 2023) [10.1109/VLSID57277.2023.00077].

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